

Dual N-channel MOSFET with schottky diode

ELM14900AA-N

General description

ELM14900AA-N uses advanced trench technology to provide excellent $R_{ds(on)}$ and low gate charge.

Features

- $V_{ds}=30V$
 - $I_d=6.9A$ ($V_{gs}=10V$)
 - $R_{ds(on)} < 27m\Omega$ ($V_{gs}=10V$)
 - $R_{ds(on)} < 32m\Omega$ ($V_{gs}=4.5V$)
 - $R_{ds(on)} < 50m\Omega$ ($V_{gs}=2.5V$)
- Schottky diode
- $V_{ds(V)}=30V$
 - $I_f=3A$
 - $V_f = 0.5V@1A$

Maximum absolute ratings

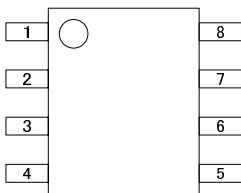
Parameter	Symbol	MOSFET	Schottky	Unit	Note
Drain-source voltage	V_{ds}	30		V	
Gate-source voltage	V_{gs}	± 12		V	
Continuous drain current	I_d	$T_a=25^\circ C$	6.9	A	1
		$T_a=70^\circ C$	5.8		
Pulsed drain current	I_{dm}	40		A	2
Schottky reverse voltage	V_{ka}		30	V	
Continuous forward current	I_f	$T_a=25^\circ C$	3	A	1
		$T_a=70^\circ C$	2		
Pulsed forward current	I_{fm}		40	A	2
Power dissipation	P_d	$T_a=25^\circ C$	2.00	2.00	W
		$T_a=70^\circ C$	1.44	1.44	
Junction and storage temperature range	T_j, T_{stg}	-55 to 150	-55 to 150	$^\circ C$	

Thermal characteristics

Parameter (MOSFET)	Symbol	Typ.	Max.	Unit	Note
Maximum junction-to-ambient	$R\theta_{ja}$	$t \leq 10s$	48.0	62.5	$^\circ C/W$
Maximum junction-to-ambient		Steady-state	74.0	110.0	
Maximum junction-to-lead	$R\theta_{jl}$	35.0	40.0	$^\circ C/W$	3
Parameter (Schottky)	Symbol	Typ.	Max.	Unit	Note
Maximum junction-to-ambient	$R\theta_{ja}$	$t \leq 10s$	47.5	62.5	$^\circ C/W$
Maximum junction-to-ambient		Steady-state	71.0	110.0	
Maximum junction-to-lead	$R\theta_{jl}$	32.0	40.0	$^\circ C/W$	3

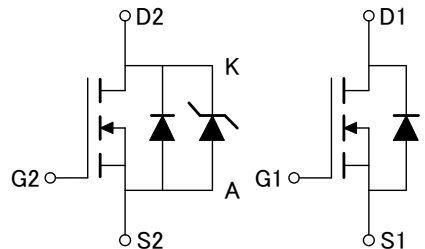
Pin configuration

SOP-8 (TOP VIEW)



Pin No.	Pin name
1	SOURCE2/ANODE
2	GATE2
3	SOURCE1
4	GATE1
5	DRAIN1
6	DRAIN1
7	DRAIN2/CATHODE
8	DRAIN2/CATHODE

Circuit



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Electrical characteristics

T_a=25°C

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit	
STATIC PARAMETERS							
Drain-source breakdown voltage	BV _{dss}	I _d =250 μA, V _{gs} =0V	30			V	
Zero gate voltage drain current	I _{dss}	V _d =24V			1	μA	
		V _{gs} =0V			5		
		T _j =55°C					
Gate-body leakage current	I _{gss}	V _d =0V, V _{gs} =±12V			100	nA	
Gate threshold voltage	V _{gs(th)}	V _d =V _{gs} , I _d =250 μA	0.7	1.0	1.4	V	
On state drain current	I _{d(on)}	V _{gs} =4.5V, V _d =5V	25			A	
Static drain-source on-resistance	R _{ds(on)}	V _{gs} =10V			22.6	27.0	
		I _d =6.9A			33.0	40.0	
			T _j =125°C				mΩ
		V _{gs} =4.5V, I _d =6A			27.0	32.0	
		V _{gs} =2.5V, I _d =5A			42.0	50.0	
						mΩ	
Forward transconductance	G _{fs}	V _d =5V, I _d =5A	12	16		S	
Diode forward voltage	V _{sd}	I _s =1A		0.71	1.00	V	
Max. body-diode continuous current	I _s				3	A	
DYNAMIC PARAMETERS							
Input capacitance	C _{iss}			846	1050	pF	
Output capacitance	C _{oss}	V _{gs} =0V, V _d =15V, f=1MHz		96		pF	
Reverse transfer capacitance	C _{rss}			67		pF	
Gate resistance	R _g	V _{gs} =0V, V _d =0V, f=1MHz		1.24	3.60	Ω	
SWITCHING PARAMETERS							
Total gate charge	Q _g			9.60	12.00	nC	
Gate-source charge	Q _{gs}	V _{gs} =4.5V, V _d =15V, I _d =6.9A		1.65		nC	
Gate-drain charge	Q _{gd}			3.00		nC	
Turn-on delay time	t _{d(on)}			3.2	4.8	ns	
Turn-on rise time	t _r	V _{gs} =10V, V _d =15V		4.1	6.2	ns	
Turn-off delay time	t _{d(off)}	R _l =2.2 Ω, R _{gen} =3 Ω		26.3	40.0	ns	
Turn-off fall time	t _f			3.7	5.5	ns	
Body diode reverse recovery time	t _{rr}	I _f =5A, dl/dt=100A/μs		15.5	20.0	ns	
Body diode reverse recovery charge	Q _{rr}	I _f =5A, dl/dt=100A/μs		7.9		nC	
SCHOTTKY PARAMETERS							
Forward voltage drop	V _f	I _f =1A		0.45	0.50	V	
Max. reverse leakage current	I _{rm}	V _r =30V		0.007	0.050	mA	
			T _j =125°C		3.2		10.0
			T _j =150°C		12.0		20.0
Junction capacitance	C _t	V _r =15V		37		pF	

NOTE :

- The value of R_{θja} is measured with the device mounted on 1in² FR-4 board of 2oz. Copper, in still air environment with T_a=25°C. The value in any given applications depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.
- Repetitive rating, pulse width limited by junction temperature.
- The R_{θja} is the sum of the thermal impedance from junction to lead R_{θj} and lead to ambient.
- The static characteristics in Figures 1 to 6,12,14 are obtained using 80μs pulses, duty cycle 0.5%max.
- These tests are performed with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_a=25°C. The SOA curve provides a single pulse rating.

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Typical electrical and thermal characteristics

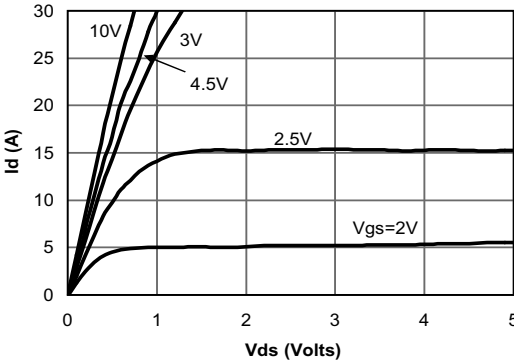


Fig 1: On-Region Characteristics

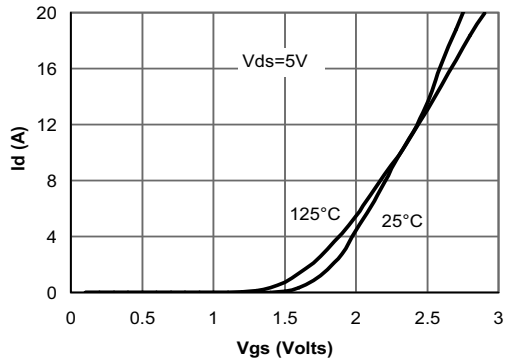


Figure 2: Transfer Characteristics

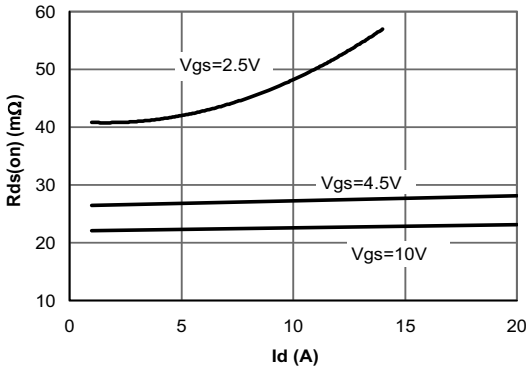


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

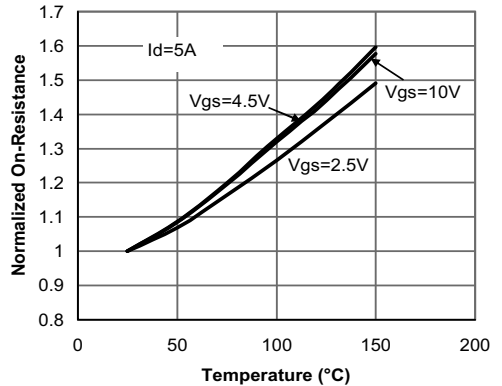


Figure 4: On resistance vs. Junction Temperature

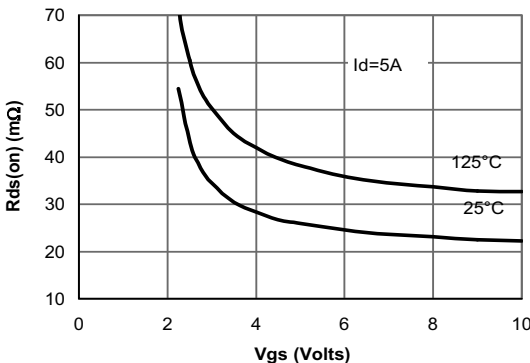


Figure 5: On resistance vs. Gate-Source Voltage

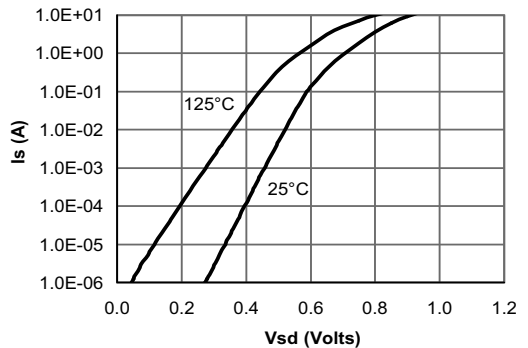


Figure 6: Body-Diode Characteristics

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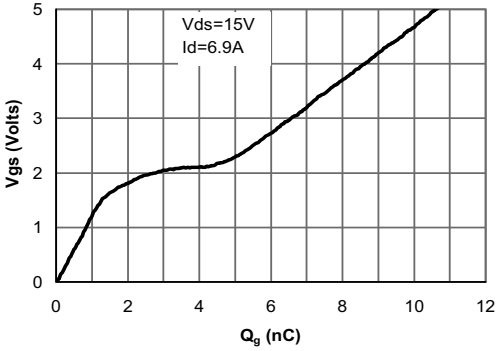


Figure 7: Gate-Charge Characteristics

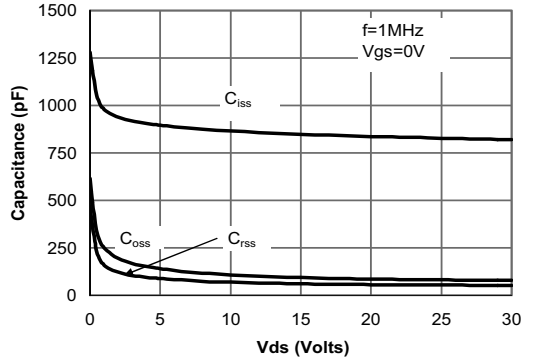


Figure 8: Capacitance Characteristics

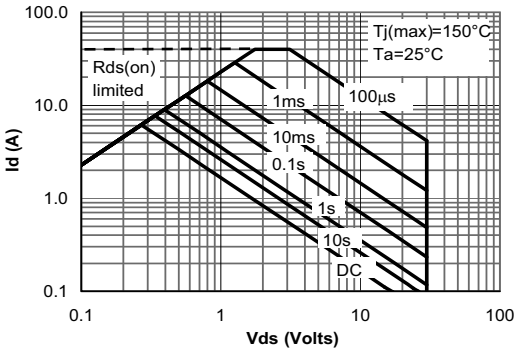


Figure 9: Maximum Forward Biased Safe Operating Area (Note 5)

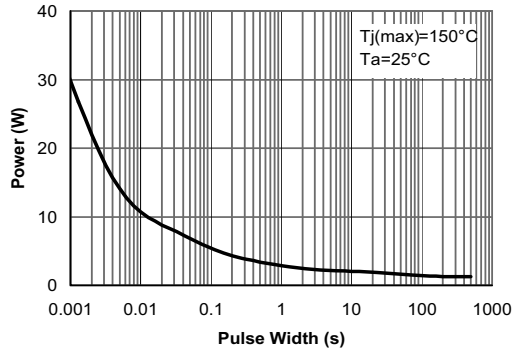


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note 5)

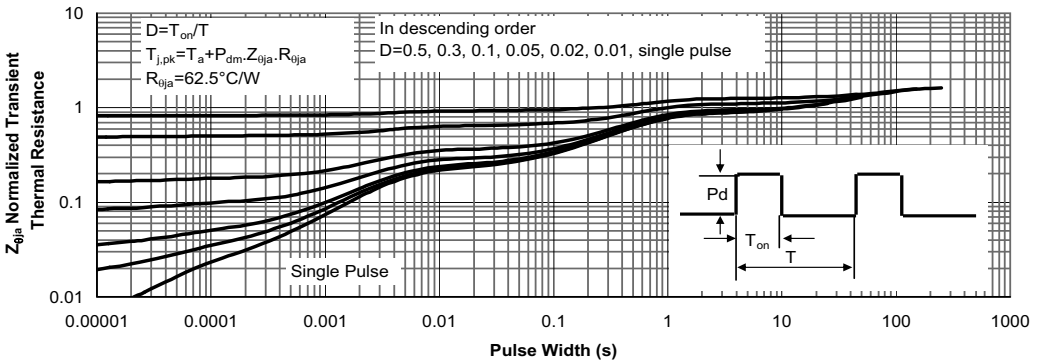


Figure 11: Normalized Maximum Transient Thermal Impedance

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Typical electrical and thermal characteristics (Schottky)

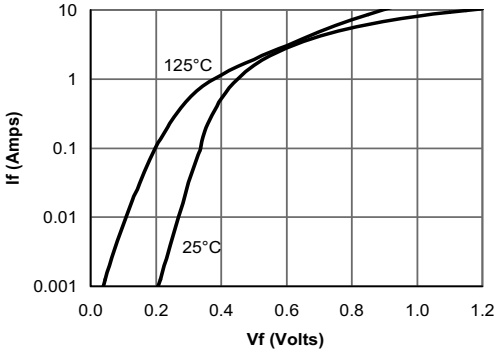


Figure 12: Schottky Forward Characteristics

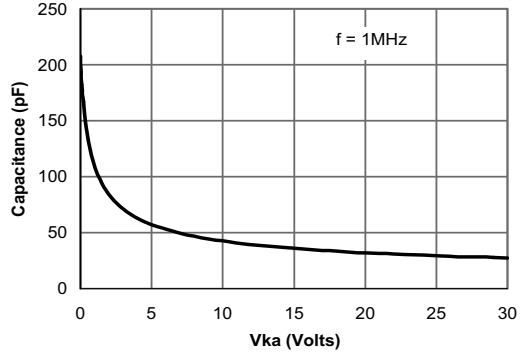


Figure 13: Schottky Capacitance Characteristics

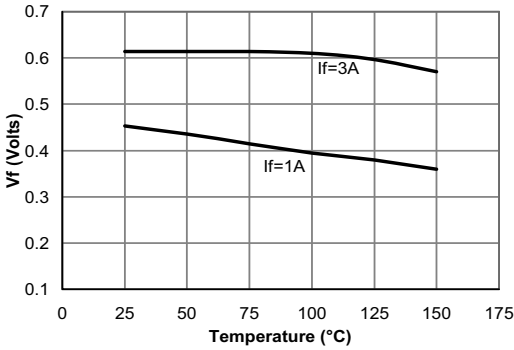


Figure 14: Schottky Forward Drop vs. Junction Temperature

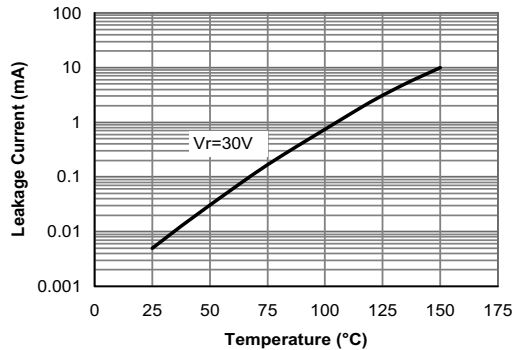


Figure 15: Schottky Leakage current vs. Junction Temperature

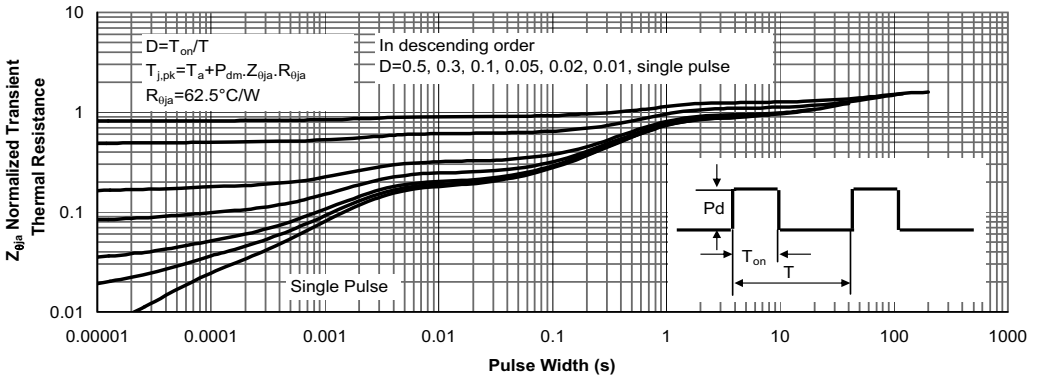


Figure 15: Schottky Normalized Maximum Transient Thermal Impedance